

EAST Search History**EAST Search History (I nterference)**

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	6	427/255.28.ccls. and (dummy or first or test) substrate and (second or bare) substrate and thick \$5	USPAT; UPAD	ADJ	ON	2009/07/21 16:04
L2	1	427/255.28.ccls. and (measur\$5 adj3 thick \$5) and (set\$4 adj3 temperature)	USPAT; UPAD	ADJ	ON	2009/07/21 16:05
L3	106	"427".clas. and (measur\$5 adj3 thick \$5) and (set\$4 adj3 temperature)	USPAT; UPAD	ADJ	ON	2009/07/21 16:06
L4	37	((first or dummy or test) substrate and (second or bare) substrate and (measur\$5 adj3 thick \$5)).clm.	USPAT; UPAD	ADJ	ON	2009/07/21 16:08
L5	1	((first or dummy or test) substrate with oxide).clm. and (second substrate with (bare or silicon)).clm. and ((measur\$5 adj3 thick\$5) or (set\$4 adj3 temperature)).clm.	USPAT; UPAD	ADJ	ON	2009/07/21 16:12

7/ 21/ 2009 4:14:33 PM
**C:\ Documents and Settings\ Ewhitehead.USPTO\ My Documents\ EAST\ Workspaces
 \ 10\ 10523803.thermal processing multiple substrates.wsp**